



Attorney Docket No.: TRAN-P283

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
Patent Application

Inventor(s): Eric Chen-Li Sheng, David Hoffman and John Laurence Niven

Application No.: 10/791099

Group Art Unit:

Filed: 03/01/04

Examiner:

Title: SYSTEM AND METHOD FOR REDUCING TEMPERATURE VARIATION DURING BURN-IN

Form 1449

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
XS	A	6035407	03/07/00	Gebara et al.	713	300	07/15/96

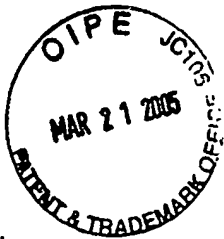
Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	B							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	C	
Examiner <i>ning</i>		Date Considered <i>5/24/05</i>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
XS	A	5,119,337	06/02/92	Shimizu et al.	365	201	04/16/90
	B	5,406,212	04/11/95	Hashinaga et al.	324	760	07/17/92
	C	5,844,429	12/1/98	Cho	327	68	07/15/96
	D	6,037,792	03/14/00	McClure	324	760	12/21/96
	E	6,100,751	08/08/00	De et al.	327	534	05/13/98
	F	6,104,061	08/15/00	Forbes et al.	257	330	02/27/98
	G	6,114,866	09/05/00	Matsuo et al.	324	760	02/04/98
	H	6,157,201	12/05/00	Leung, Jr.	324	760	01/28/98
	I	6,137,301	10/24/00	Chen	324	760	05/11/98
	J	6,218,892	04/17/01	Soumyanath et al.	327	537	02/24/99
	K	6,262,588	07/17/01	Chen	324	765	08/07/00
XS	L	6,310,485	10/30/01	McClure	324	760	01/27/00
	M						

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	N						Yes	No
	O							
	P							
	Q							
	R							
	S							

Other Documents

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